TOSHIBA Diode Silicon Epitaxial Planar Type

1SS361F

Ultra High Speed Switching Applications

Small package : 1608 Flat lead

Excellent in forward current and forward voltage characteristics $: V_{F(3)} = 0.9V \text{ (typ.)}$

Fast reverse recovery time: $t_{rr} = 1.6$ ns (typ.) Small total capacitance $: C_T = 0.9pF (typ.)$

Maximum Ratings (Ta = 25°C)

Characteristic	Symbol	Rating	Unit
Maximum (peak) reverse voltage	V_{RM}	85	V
Reverse voltage	V _R	80	V
Maximum (peak) forward current	I _{FM}	300 (*)	mA
Average forward current	Io	100 (*)	mA
Surge current (10ms)	I _{FSM}	2 (*)	Α
Power dissipation	Р	100	mW
Junction temperature	Tj	125	°C
Storage temperature range	T _{stg}	-55~125	°C

Unit rating. Total rating = unit rating \times 1.5

Unit in mm 1.6 ± 0.1 0.85 ± 0.1 1.0 ± 0.1 0.13 ± 0.05 1. ANODE1 2. ANODE2 **CATHODE ESM JEDEC** FIA.J **TOSHIBA**

Weight: 2.3 mg

Electrical Characteristics (Ta = 25°C)

Characteristic	Symbol	Test Circuit	Test Condition	Min	Тур.	Max	Unit
Forward voltage	V _{F (1)}	_	I _F = 1mA	1	0.60	_	
	V _{F (2)}	_	I _F = 10mA		0.72	_	V
	V _{F (3)}	_	I _F = 100mA	_	0.90	1.20	
Reverse current	I _{R (1)}	_	V _R = 30V	_	_	0.1	
	I _{R (2)}	_	V _R = 80V	_	_	0.5	μА
Total capacitance	C _T	_	V _R = 0, f = 1MH _z	_	0.9	3.0	pF
Reverse recovery time	t _{rr}	_	I _F = 10mA (Fig.1)	_	1.6	4.0	ns

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Fig.1 Reverse Recovery Time (trr) Test Circuit

Marking









